

interference 09/845,879

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S43	9	(functional circuitry AND test access port AND scan test port AND connection circuitry AND first gate AND tap lock or TAP lock). clm.	US-PGPUB; USPAT	ADJ	ON	2005/08/07 16:41

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	4344	714/733 or 714/734 or 714/724 or 714/726 or 714/727 or 714/30	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:17
L3	79	TAP lock	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L4	79	tap lock	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L5	0	L4 and I40	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L6	161521	flip flop	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L7	139544	"AND gate"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L8	79	L4 and (L3 or L5 or L6 or L7)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:19
L9	2	I8 and I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:20

L10	39817	data register\$1	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:21
L11	11041	instruction register	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:21
L12	3829	L10 and L11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:21
L13	278385	test access port or TAP	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23
L14	223	test mode select signal	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23
L15	11	test clock lead	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23
L16	227	lock out signal	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23
L17	7	first gate with lock out	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23

L18	79	L3 and (L13 or L14 or L15 or L16 or L17)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:23
L19	79	L4 and (L3 or L5 or L6 or L7)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:24
L20	3829	L10 and L11	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:25
L21	43	scan test port	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:26
L22	2813	connection circuitry	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:26
L23	1468	functional circuitry	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:26
L24	278385	test access port or TAP	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:28
L25	444	I24 and (I21 or I22 or I23 or I18)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:29

L26	134	I25 and (I12 or I8)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:30
L27	36	I26 and I2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:30
L28	36	I27 and I20	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	ADJ	ON	2005/08/07 19:31